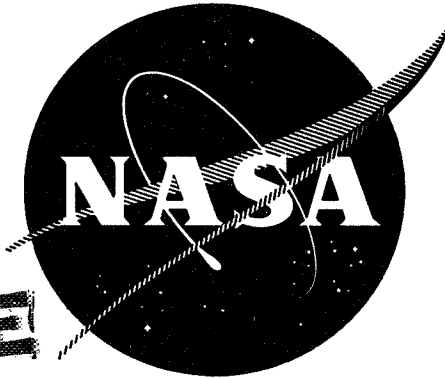




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EVALUATION PROGRAM

for

SECONDARY SPACECRAFT CELLS

**EVALUATION OF STORAGE METHODS,
OPEN CIRCUIT VERSUS CONTINUOUS TRICKLE CHARGE,
SONOTONE 3.5 AMPERE-HOUR SEALED NICKEL-CADMIUM
SECONDARY SPACECRAFT CELLS**

**prepared for
GODDARD SPACE FLIGHT CENTER
CONTRACT W12,397**



**QUALITY EVALUATION LABORATORY
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Enclosure (1)

REPORT BRIEF
EVALUATION OF STORAGE METHODS
OPEN CIRCUIT VERSUS CONTINUOUS TRICKLE CHARGE,
SONOTONE 3.5 AMPERE-HOUR SEALED NICKEL-CADMIUM
SECONDARY SPACECRAFT CELLS

- Ref: (a) National Aeronautics and Space Administration Purchase Order Number W12,397
(b) NASA ltr BRA/VBK/pad of 25 September 1961 w/BUWEPS first end FQ-1:WSK of 20 October 1961 to CO NAD Crane
(c) Preliminary Work Statement for Battery Evaluation Program of 25 August 1961

I. TEST ASSIGNMENT BRIEF

A. In compliance with references (a) and (b) evaluation of methods for storage of nickel-cadmium cells at room ambient conditions was begun on 27 February 1966 according to the program outline of reference (c). The nickel-cadmium cells used for this test were 3.5 ampere-hour "D" cells manufactured by the Sonotone Corporation.

B. The overall object of these evaluation programs is to gather specific information concerning secondary spacecraft cells. Information concerning performance characteristics and limitations including cycle life under various electrical and environmental conditions will be of interest to power systems designers and users. Cell weaknesses, including causes of failure of designs, will be of interest to suppliers as a guide to product improvement.

C. The specific purpose of this 5-year test is to compare, after each successive 1-year storage period, the discharge and charge characteristics of charged cells on open circuit versus that of cells on continuous trickle charge.

D. Of the original 25 cells subjected to the acceptance tests, 20 were selected for this storage test. Following recharge, after completion of the acceptance tests, 10 cells were placed on open circuit stand and 10 were placed on continuous trickle charge at the c/100 rate.

E. Following completion of each year of storage, the cells were subjected to the standard acceptance test sequence. However, no cells were rejected or removed from the storage test on the basis of this testing sequence. These tests, after each year of storage, serve as a means of reporting the condition of the cells as the test

continues and aids in the selection of a cell of lower capacity of each storage method for analysis at the end of each yearly storage period.

1. Data of the acceptance test sequence following completion of the third 1-year storage period is contained in this report accompanied by summaries and data accumulated from the start of the storage testing.

2. Following removal of one cell of each storage method after each 1-year storage period, the remainder of the cells were recharged and shelved for the following 1-year storage period.

II. CONCLUSIONS

A. The results of the first 3 years of this storage test show the following:

1. The initial capacities of charged cells following the first, second and third 1-year open circuit periods are unreliable. They varied from zero to 62 percent of the average acceptance capacity as determined before the start of the storage testing.

2. The initial capacities of charged cells following the first, second and third 1-year trickle charge storage periods are reliable. They averaged 78, 75, and 84 percent respectively of the average acceptance capacity as determined before the start of the storage testing.

3. Conversely, the second and third discharge capacities of cells following successive yearly open circuit storage periods are reliable, and averaged considerably higher than the capacities of cells following the first 2 years (only slightly higher the third year) of trickle charge storage. The capacities of the open circuit storage tests following recharge continue to be slightly greater than those of the trickle charge tests. However, this difference has declined each year thus far.

4. Postmortem analysis on the cell removed from the open circuit storage test showed that the electrolyte was not uniformly distributed. There were dry, less pliable spots in the separator material. In the wet portions the migration was more extensive. This indicates that only the wet portions of the cell are being worked - resulting in lower capacity. This further indicates that briefly cycling the cells on open circuit storage would likely restore capacity by redistributing the electrolyte. Thus a portion of the overall capacity difference noted in the previous paragraph would be restored. Postmortem analysis also indicates that reconditioning cycles would be unlikely to revitalize the cells on the

trickle charge storage test. This is due to more general migration and visible degradation observed in these cells.

B. The ceramic seals of these cells revealed four leakers for the open circuit storage cells and six leakers for the trickle charge storage cells. These 10 leakers out of the 16 cells on test were discovered at the completion of the third 1-year storage period. This was the first indication of leaks to that time.

EVALUATION OF STORAGE METHODS,
OPEN CIRCUIT VERSUS CONTINUOUS TRICKLE CHARGE,
SONOTONE 3.5 AMPERE-HOUR SEALED NICKEL-CADMIUM
SECONDARY SPACECRAFT CELLS

I. INTRODUCTION

A. On 8 July 1969, tests were begun on 16 cells following the third 1-year storage period. The testing sequence was completed on 7 August 1969; two cells were removed for postmortem analysis; and the remaining 14 cells were returned to their respective storage tests.

II. TEST CONDITIONS

A. All tests were performed at an ambient temperature between 23° C and 27° C at existing relative humidity and atmospheric pressure, and consisted of the following:

1. Phenolphthalein Leak Test.
2. Capacity Test.
3. Cell Short Test.
4. Immersion Seal Test.
5. Overcharge Test.
6. Internal Resistance Test.
7. Immersion Seal Test.
8. Visual Postmortem.

B. All charging and discharging were done at constant current (± 5 percent). Cells were charged in series but discharged individually.

III. CELL IDENTIFICATION AND DESCRIPTION

A. The cells were identified by the manufacturer's serial numbers which were from A-2491 to A-2551 although not consecutively.

B. The 3.5 ampere-hour "D" cell is cylindrical with an average diameter of 1.306 inches and an average overall length of 2.387 inches including the positive terminal. The average weight was 158.8 grams. Figure 1 is a photograph of a Sonotone Corporation 3.5 ampere-hour "D" cell.

C. The cell container or can, and the cell cover are made of stainless steel. A stainless steel tab, welded to the cover, serves as a contact for the negative terminal. The positive terminal is a solder type extension of the positive plate tab, through the center of the cover. The positive terminal is insulated from the "negative" cover by a ceramic seal. Two crimp rings, about 1/32 inch deep, located about 9/16 inch from each end of the cell, were crimped after assembly to hold the element snugly in the can to withstand vibration.

D. These 16 cells, rated by the manufacturer at 3.5 ampere-hours, have completed three 1-year storage periods at 25° C. Eight of the cells have been on open circuit stand during the last year in the charged state. The other eight cells have been on continuous over-charge during the last year at the c/100 rate (35 milliamperes).

IV. TEST PROCEDURE AND RESULTS

A. Phenolphthalein Leak Test:

1. The phenolphthalein leak test is a determination of the condition of the welds and ceramic seals prior to any electrical tests. This test was performed with a phenolphthalein spray indicator solution of one-half of one percent concentration.

2. Following the third 1-year storage, the group of cells on yearly open circuit gave initial evidence of four leakers; the group on yearly trickle charge gave evidence of six leakers. All leaks occurred around the positive post. This was the first indication of leaks.

3. Table I gives a summary of the noted leakers.

B. Capacity Test:

1. Upon receipt, the cells were subjected to the acceptance tests which included three capacity checks. The capacity test is a determination of the cell capacity at the c/2 discharge rate, where c is the manufacturer's rated capacity, to a cutoff voltage of 1.00 volt per cell.

a. The discharge of each of the three original capacity checks followed a 1-hour open circuit period after a 16-hour charge at the c/10 rate.

b. For the series of three capacity checks following each 1-year period of the respective storage method, the first consisted on an immediate discharge to 1.00 volt per cell at the

c/2 rate. The second and third capacity discharge checks followed a 1-hour open circuit period after a 16-hour charge at the c/10 rate.

2. Open Circuit Storage Test:

a. The capacities of the first capacity check of the 10 cells picked for the 1-year open circuit storage periods averaged 3.90 ampere-hours. This was used as 100 percent capacity for the start of the test. All following capacities or averages thereof are plotted on the graphs as percentages of the initial average capacity. Following recharges, the second and third capacity checks averaged 3.80 and 3.61 ampere-hours for 97.5 and 92.5 percent respectively of the first capacity test.

b. Following the third 1-year stand (1969), the eight cells remaining, after two yearly postmortem removals, were discharged to 1.00 volt per cell at the c/2 rate. This first of three capacity checks resulted in capacities ranging from 0.0 to 1.35 ampere-hours for an average of 0.273 or approximately 7.0 percent of the initial capacity. The capacities of the second and third capacity checks, following recharges, averaged 3.04 and 2.66 ampere-hours respectively for approximately 78 and 68 percent of the initial capacity. Disregarding cell A-2495 which was removed for postmortem analysis, the second and third capacity checks following recharges, were respectively 81.5 and 71.5 percent of the initial capacity. In 1967 these respective averages were 41.5, 91.0, and 85.0 percent of the initial capacity. In 1968 the percentages were 31.0, 82.0 and 82.0 percent of the initial capacity.

c. The preceeding information shows that the initial capacities of charged cells left on 1-year open circuit stands at 25° C are unreliable. However, the capacities of these cells, following recharges after the first 1-year open circuit stand are all high - averaging 84 percent of the initial capacity on the third capacity check. The second and third 1-year stands (with one low capacity exception each year) also displayed good capacities - averaging 76 and 68 percent of initial capacity, each respective year, on the third capacity check.

d. The capacity test data of cells on successive 1-year open circuit storage periods is given in Table II and shown graphically in Figure 2.

3. Trickle Charge Storage Test:

a. The capacities of the first capacity check of the 10 cells picked for the 1-year trickle charge storage periods averaged

3.92 ampere-hours. This was used as 100 percent capacity for the start of the test. All following capacities or averages thereof are plotted on the graphs as percentages of the initial average capacity. Following recharges, the second and third capacity checks averaged 3.81 and 3.59 ampere-hours for 97.2 and 91.6 percent respectively of the first capacity test.

b. Following the third 1-year trickle charge storage period (1969) and following a 1-hour open circuit period, the eight cells remaining, after two yearly postmortem removals, were discharged to 1.00 volt per cell at the $c/2$ rate. The first of the three capacity checks ranged from 1.97 to 3.77 ampere-hours for an average of 3.30 ampere-hours or about 85 percent of the initial capacity. The capacities of the second and third capacity checks, following recharges, averaged 2.85 and 2.56 ampere-hours respectively for about 74 and 66 percent of the initial capacity. By disregarding the low capacity of cell A2547 (removed for postmortem analysis), the percent of initial capacity for the three capacity checks are respectively 89.5, 76.1, and 68.9 percent. In 1967 these respective averages were 78.0, 63.0 and 63.0 percent of the initial capacity. In 1968 the percentages were 75.0, 66.0, and 73.0 percent of the initial capacity.

c. The preceding information shows that the initial capacities of charged cells left on yearly trickle charge storage periods at the $c/100$ are still highly reliable after 3 years of such storage. However the reliability is down somewhat from the previous year due to one of the eight cells (A2547) showing low capacity. Further the trickle charge method of storage still tends to give less capacity than the open circuit method following recharges; but the difference in capacity between these two storage methods is less each year. Compare the average and percentage data for the two storage methods in Table II. Notice, the percent of initial capacity for the second and third capacity checks continually shows less difference between the storage methods as time proceeds.

d. The capacity test data of charged cells on successive 1-year trickle charge storage periods is given in Table II and shown graphically in Figure 3.

C. Cell Short Test:

1. The cell short test is a means of detecting slight shorting conditions which may exist in a cell because of imperfections in the insulating materials, or damage to element in handling or assembly; or which may develop in cells due to deterioration of the insulation materials during service life.

2. Following completion of the third capacity discharge test, prior to the start of each yearly storage period, each individual cell was loaded with a resistor of value giving a c/1 to c/5 discharge rate. Each cell was allowed to stand 16 hours with the resistor acting as a shorting device. At the end of 16 hours, the resistors were removed and the cells allowed to stand on open circuit for 24 hours. Under the regular acceptance test procedure used prior to start of the first 1-year storage period, any cell whose voltage did not recover to a minimum of 1.15 was rejected. However due to the nature of this series of successive 1-year storage periods, cells with recovery voltages less than 1.15 after each yearly storage period are not rejected or removed from succeeding tests.

3. The recovery voltages for the cells, prior to the start of the storage test, ranged from 1.21 to 1.24 volts for an average of 1.22 volts per cell.

4. The recovery voltages for the cells after the first 1-year period under either storage method averaged 1.21 volts per cell.

5. Following the second 1-year open circuit storage period, the open circuit voltage of each of two cells failed to recover significantly above zero volt. However, the recovery voltage of cells following the second 1-year trickle charge storage period averaged 1.21 volts.

6. Following the third 1-year open circuit storage period, the open circuit voltage of each of two cells was zero. However, the recovery voltage of cells following the third 1-year trickle charge storage period again averaged 1.21 volts.

7. The recovery voltages values following the cell short test are given in Table III.

D. Immersion Seal Test:

1. The immersion seal test is a means of detecting leakage of a seal or weld. The test was performed before and after the over-charge test during the acceptance test sequence prior to start of each 1-year storage period to determine the presence and cause of leaks.

2. The cells were placed under water in a bell jar container. A vacuum of 20 inches of mercury was held for 3 minutes. Tests are to be discontinued on cells discharging a steady stream of bubbles.

3. There were no detectable leaks by this method after the third 1-year storage period. However phenolphthalein tests gave leak indications as explained in paragraph IV.A.2. and summarized in Table I.

E. Overcharge Test:

1. The overcharge tests were performed to determine the steady state voltage at specified rates. The test specified a series of three successive constant current charges at the $c/20$, $c/10$ and $c/5$ rates in order. The charge at each rate was for a minimum of 48 hours or until the increase of the on-charge voltage was less than 10 millivolts per day. Upon completion of 48 hours of charge at each of the lower rates, the charge rate was increased to the next higher specified rate. These tests were performed prior to start of the storage test, and after each successive yearly storage period under each storage method.

2. The cells were monitored hourly throughout the overcharge test. Under regular acceptance testing, the test procedure requires that charging be discontinued on cells which exceed 1.50 volts, the maximum specified on-charge voltage. However, for this test, charging of a few cells was discontinued when their on-charge voltages exceeded the revised voltage limit of 1.55 but none were rejected or removed from the test.

a. During the overcharge test prior to the first 1-year storage period, charging was discontinued on two of the 20 cells when the voltage exceeded 1.55 volts after 10 hours at the $c/5$ rate.

b. During the overcharge test after the first 1-year storage periods:

(1) Only one of the open circuit stored cells exceeded 1.55 volts at the $c/10$ rate. It was removed from the charging circuit after 7 hours of charge, and was not subjected to overcharging at the $c/5$ rate.

(2) The highest on-charge cell voltage reached by trickle charge stored cells was 1.42 while charging at the $c/5$ rate.

c. During the overcharge test after the second 1-year storage periods:

(1) Only two of the open circuit stored cells exceeded 1.55 volts for a few hours. The cells were allowed to continue the overcharge sequence and did not exceed 1.55 volts at either the $c/10$ or $c/5$ charge rates.

(2) The highest on-charge cell voltage reached by trickle charge stored cells was 1.50 while charging at the c/5 rate.

d. During the overcharge test after the third 1-year storage periods:

(1) Only one of the open circuit stored cells exceeded 1.55 volts when the rate was increased from c/20 to c/10. This occurred only during the first hour following the increase in charge rate; the voltage then dropped to 1.55 volts and gradually continued to decline to 1.41 volts just prior to the beginning of the c/5 overcharge rate.

(2) The highest on-charge cell voltage reached by trickle charge stored cells was 1.43 while charging at both the c/10 and the c/5 rate.

3. The average on-charge voltages during the overcharge periods of the cells stored under each of the storage methods are shown graphically in Figure 4. This graph indicates that:

a. Under either method of storage, the average of the on-charge cell voltages are higher during the overcharge period before start of the storage test than during the overcharge periods following any of the three 1-year storage periods.

b. Under the open circuit storage method, the average of the on-charge voltages during the overcharge periods following each 1-year storage period was less than that of the previous year for the first 2 years. However this trend was broken in the third year. The average on-charge voltage during this overcharge period lies between the initial (acceptance) values and those of the second 1-year period.

c. Under the trickle charge storage method, at the end of the first 1-year storage period, the overcharge voltages averaged considerably less than those of the initial acceptance testing. After the second 1-year storage period, the on-charge voltages had increased until they were only slightly less than those of the initial acceptance overcharge tests. After the third 1-year storage period, the on-charge cell voltages average slightly more than the first 1-year period and slightly less than the second 1-year period. No overall trend is obvious as yet.

F. Internal Resistance Test:

1. This test was performed to determine the internal resistance of the cells.

2. At the completion of the overcharge test; the cells were returned to the c/20 charging rate and given a short pulse (5-10 seconds) at the c/1 charge rate. The cell voltages, V_1 , immediately prior to the pulse; and V_2 , 5 milliseconds after the initiation of the pulse were read on a CEC high-speed oscillograph recorder (16.0 inches of tape per second). The internal resistance of the cell in ohms was calculated according to the following formula:

$$R = \frac{V_2 - V_1}{I_c - I_c/20}$$

V_1 and V_2 are in volts (read to the nearest 0.01 volt); I_c and $I_c/20$ are in amperes (read to the nearest 0.001 ampere).

3. The internal resistance value for each cell is shown in Table IV. Due to the number of significant figures in the voltage measurements, the error in the resistance values is very large (on the order of 10 milliohms). Therefore, it is difficult to obtain any meaningful results for comparative purposes from the resistance data as computed. For these reasons, a Hewlett-Packard 4328A milliohmmeter was employed to measure the internal resistance directly in an effort to furnish more reliable data for present and future comparisons.

G. Visual Postmortem:

1. Following completion of tests after the third 1-year storage period, cell A2495 from the open circuit portion and cell A2547 from the c/100 trickle charge portion of the 1-year test were opened.

a. The cell subjected to the open circuit test had the following visual characteristics:

(1) The separator material was very dry in spots and somewhat leathery with very light yellowish discolorations in the wet areas. The reason for these variations was the inactivity of these cells resulting in improper electrolyte distribution.

(2) Migration was more extensive in the wet portions of the separator material and under the scoring areas.

(3) Both positive and negative plates displayed normal flexibility with no visible loss of active material.

b. The cell subjected to the c/100 trickle charge test had the following visual characteristics:

(1) The moisture content was uniform throughout the separator material - a result of continual redistribution of electrolyte.

(2) Migration was more extensive and more general than that found in cell A2495. The migration was heaviest in the scored areas.

(3) Both positive and negative plates displayed normal flexibility with no visible loss of active material.

2. Following completion of tests after the second 1-year storage period, cell A-2526 from the open circuit portion and cell A-2559 from the c/100 overcharge portion of the 1-year test were opened.

a. The cell subjected to the open circuit test had the following visual characteristics:

(1) The separator material was considerably less pliable than normal with considerable migrated active material on the side adjacent to the positive plate. The heaviest migration was under the scoring area.

(2) The positive plate had normal flexibility with no visible loss of active material.

b. The cell subjected to the c/100 trickle charge test had the following visual characteristics:

(1) The separator material was very pliable with very little migration on any portion of the separator.

(2) The positive plate was less flexible than normal and had little visible loss of active material.

3. For purposes of comparison, the following information on the postmortem of cells A-2536 and A-2564 following completion of tests after the first 1-year storage period is given.

a. Cell A-2536, subjected to the open circuit test had the following visual characteristics:

(1) The separator material was considerably less pliable than normal with considerable migration against the positive plate. The heaviest migration was under the scoring area.

(2) The positive plate was less flexible than normal and had little visible loss of active material.

(3) The negative plate had normal flexibility but had a discoloration on approximately 1/3 of the plate length starting at the center of the core.

b. Cell A-2564, subjected to the c/100 trickle charge test had the following visual characteristics:

(1) The separator material was very pliable with very little migration on any portion of the separator.

(2) The positive plate had normal flexibility with no visible loss of active material.

(3) The negative plate had normal flexibility with no visible discoloration.

TABLE I
TESTS: INITIAL AND AFTER OVERCHARGE
PHENOLPHTHLEIN

Group on Yearly Open Circuit Stand

Cell Number	Initial				After Overcharge				Immersion*
	Terminals		Seals		Terminals		Seals		
	+	-	Top	Other	+	-	Top	Other	
A-2491									
A-2492	L				L				
A-2493									
A-2494	v.s.				L				
A-2495									
A-2498									
A-2503	v.s.				L				
A-2508	L								

Group on Yearly Trickle Charge

A-2540	L				L				
A-2542	L				L				
A-2544	L				L				
A-2545	L				L				
A-2546									
A-2547	v.s.				L				
A-2548	v.s.								
A-2551									

L - Definite Leak

v.s. - Very Slight

*Immersion tests gave no indication of leaks. The phenolphthleuin tests are much more sensitive.

TABLE II
CAPACITY TESTS

	Cell Number	Before Storage Periods			After First 1-Year Storage Period Ampere-Hours			After Second 1-Year Storage Period Ampere-Hours		
		Ampere-Hours			Without Charge 1st	After Recharge 2nd	After Recharge 3rd	Without Charge 1st	After Recharge 2nd	After Recharge 3rd
		1st	2nd	3rd						
1-YEAR OPEN CIRCUIT STANDS	A-2491 ●	4.34	4.29	4.11	2.01	3.90	3.55	1.54	3.50	3.50
	A-2492 □	4.06	4.15	4.03	0.02	2.73	3.68	0.00	3.70	3.64
	A-2493 ▲	3.64	3.50	3.33	2.13	3.46	3.29	1.84	3.24	3.22
	A-2494 ▼	4.11	4.06	3.94	2.33	3.71	3.58	1.79	3.26	3.32
	A-2495 ○	2.98	2.80	2.58	0.02	2.33	2.22	0.04	1.83	0.74
	A-2498 X	3.69	3.37	3.17	1.72	3.71	3.26	2.31	3.76	3.36
	A-2503 ◇	4.29	4.17	3.80	2.01	3.70	3.26	0.00	2.97	2.80
	A-2508 ♥	3.89	3.97	3.80	2.37	3.42	3.23	1.70	3.10	3.01
	A-2526 ⊕	4.15	4.06	3.97	2.28	4.03	3.85	1.61	2.71	3.36
	A-2536 ♣	3.82	3.64	3.36	1.31	3.38	3.06	--	--	--
	AVERAGE	3.90	3.80	3.61	1.62	3.54	3.30	1.20	3.12	2.99
	PERCENT	100.0	97.5	92.5	41.5	90.8	84.6	30.7	80.0	76.8
1-YEAR OVERCHARGE PERIODS AT c/100	A-2540 ●	3.99	3.99	3.99	3.24	2.75	2.83	3.12	2.97	3.10
	A-2542 □	4.17	4.15	3.89	2.65	2.21	2.45	3.18	2.93	3.03
	A-2544 ▲	3.99	3.82	3.73	3.20	2.61	2.59	2.28	2.31	2.33
	A-2545 ▼	3.78	3.50	3.25	2.97	2.21	2.18	3.21	2.86	2.76
	A-2546 ○	4.41	4.20	3.80	2.83	2.43	2.51	2.98	2.93	3.03
	A-2547 X	3.50	3.20	2.92	2.33	1.75	1.77	2.28	2.02	2.06
	A-2548 ◇	3.81	3.75	3.47	3.38	2.71	2.47	2.76	1.68	2.84
	A-2557 ♥	3.76	3.80	3.54	3.73	2.89	2.85	3.21	3.15	3.29
	A-2559 ⊕	3.76	3.90	3.76	3.73	2.85	2.74	3.29	2.42	3.18
	A-2564 ♣	4.03	3.82	3.59	2.53	2.14	2.15	--	--	--
	AVERAGE	3.92	3.81	3.59	3.06	2.45	2.45	2.92	2.59	2.85
	PERCENT	100.0	97.2	91.6	78.0	62.5	62.5	74.5	66.5	72.7

TABLE II (cont)
CAPACITY TESTS

		After Third 1-Year Storage Period Ampere-Hours		
Cell Number		Without Charge 1st	After Recharge 2nd	After Recharge 3rd
1-YEAR OPEN CIRCUIT STANDS	A-2491 ●	0.79	3.18	2.94
	A-2492 □	0.05	3.45	3.27
	A-2493 △	0.00	3.50	3.27
	A-2494 ▽	0.00	3.15	2.54
	A-2495 ○	0.00	2.05	1.72
	A-2498 ✕	1.35	3.20	2.97
	A-2503 ◇	0.00	2.57	2.18
	A-2508 ♥	0.00	3.20	2.36
	A-2526 ⊕	--	--	--
	A-2536 ▲	--	--	--
	AVERAGE	0.27	3.04	2.66
	PERCENT	1.0	77.9	68.2
1-YEAR OVERCHARGE PERIODS AT c/100	A-2540 ●	3.77	3.21	3.29
	A-2542 □	3.55	3.02	2.80
	A-2544 △	3.24	2.76	2.40
	A-2545 ▽	3.72	3.02	2.68
	A-2546 ○	3.29	2.66	2.50
	A-2547 ✕	1.97	2.05	1.67
	A-2548 ◇	3.27	2.76	2.57
	A-2557 ♥	3.54	3.33	3.20
	A-2559 ⊕	--	--	--
	A-2564 ▲	--	--	--
	AVERAGE	3.30	2.85	2.64
	PERCENT	84.2	72.7	67.3

TABLE III
CELL SHORT TEST
RECOVERY VOLTAGES

Cell Number	Before Storage Test	After First 1-Year Storage Test	After Second 1-Year Storage Test	After Third 1-Year Storage Test
A-2491	1.21	1.20	1.20	1.20
A-2492	1.23	1.21	0.02	0.01
A-2493	1.23	1.21	1.21	1.21
A-2494	1.22	1.22	1.21	1.21
A-2495	1.22	1.20	1.19	1.21
A-2498	1.22	1.22	1.20	1.19
A-2503	1.22	1.21	1.22	1.21
A-2508	1.22	1.21	0.00	0.01
A-2526	1.22	1.20	*	--
A-2536	1.23	1.22	--	--
AVERAGE	1.22	1.21		.906**
A-2540	1.23	1.20	1.21	1.21
A-2542	1.22	1.19	1.21	1.19
A-2544	1.22	1.22	1.20	1.19
A-2545	1.22	1.22	1.23	1.21
A-2546	1.23	1.19	1.20	1.20
A-2547	1.22	1.23	1.24	1.23
A-2548	1.24	1.22	1.23	1.23
A-2557	1.22	1.21	1.21	1.21
A-2559	1.21	1.21	1.22	--
A-2564	1.23	1.23	--	--
AVERAGE	1.22	1.21	1.217	1.21

* Missed in error

**Average without low cells - 1.21 volts

TABLE IV
INTERNAL RESISTANCE (Milliohms)

Cell Number	Before Storage Test	After First 1-Year Storage Test	After Second 1-Year Storage Test	After Third 1-Year Storage Test Compu- tation	Milliohm- meter
A-2491	6.02	12.03	12.04	9.03	13.4
A-2492	9.02	12.03	12.04	9.03	16.0
A-2493	15.03	18.04	15.05	6.02	21.5
A-2494	6.02	15.03	12.04	6.02	15.0
A-2495	6.02	18.04	21.07	15.0	14.8
A-2498	6.02	18.04	6.02	9.03	27.6
A-2503	9.02	15.03	15.05	12.0	14.5
A-2508	9.02	12.03	9.03	9.03	13.6
A-2526	3.01	12.03	6.02	--	--
A-2536	3.01	12.03	--	--	--
AVERAGE	7.22	14.43	12.04	9.40	17.1
A-2540	6.02	15.03	6.02	9.03	15.0
A-2542	3.01	15.03	12.04	3.01	11.5
A-2544	6.02	15.03	15.05	6.02	14.5
A-2545	6.02	18.04	9.03	3.01	18.0
A-2546	3.01	15.03	12.04	3.01	36.0
A-2547	6.02	21.05	21.07	9.03	13.5
A-2548	6.02	15.03	9.03	6.02	16.0
A-2557	6.02	15.03	15.05	6.02	19.5
A-2559	3.01	18.04	9.03	--	--
A-2564	3.01	15.03	--	--	--
AVERAGE	4.81	16.23	12.04	5.64	18.0

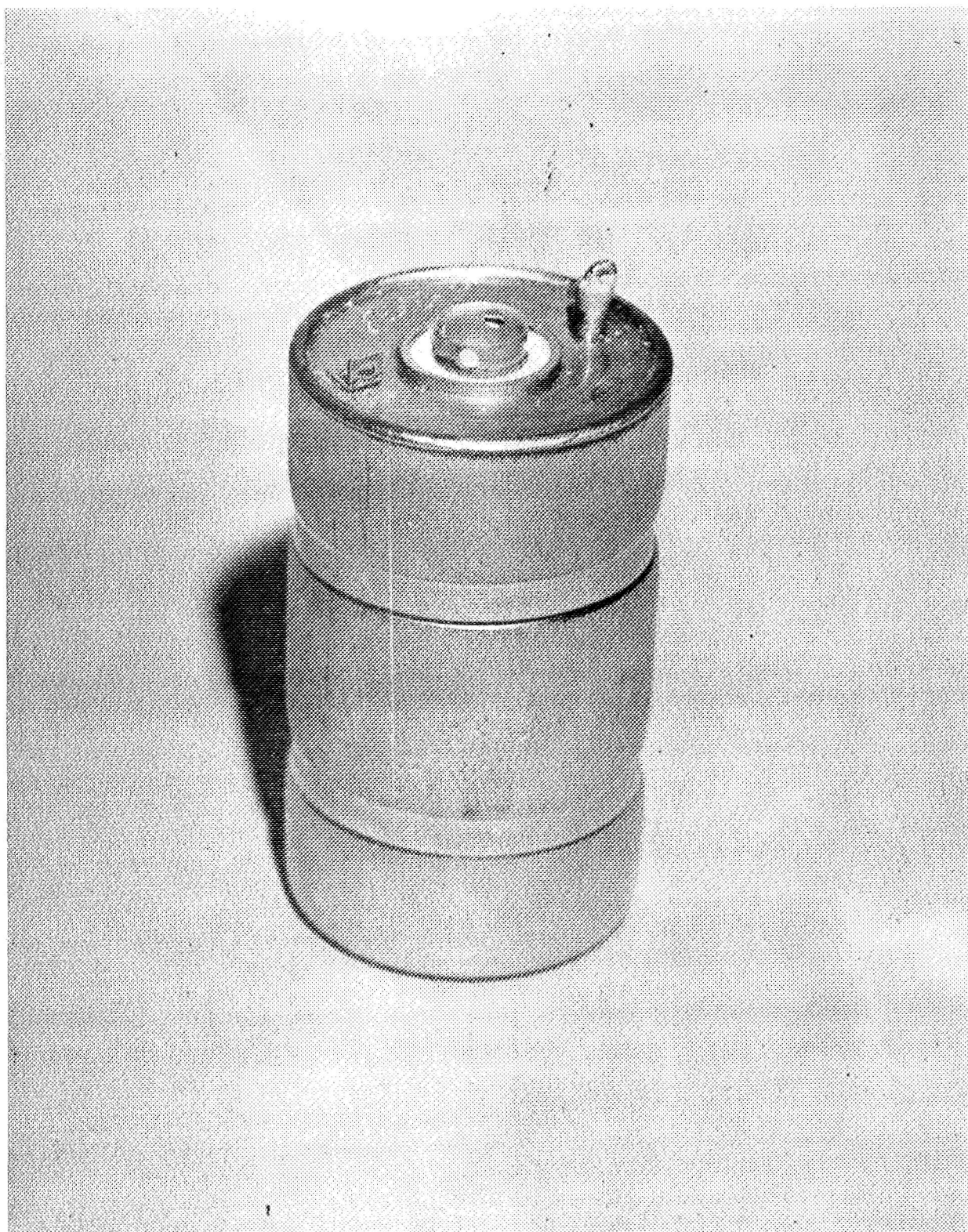


FIGURE 1
16

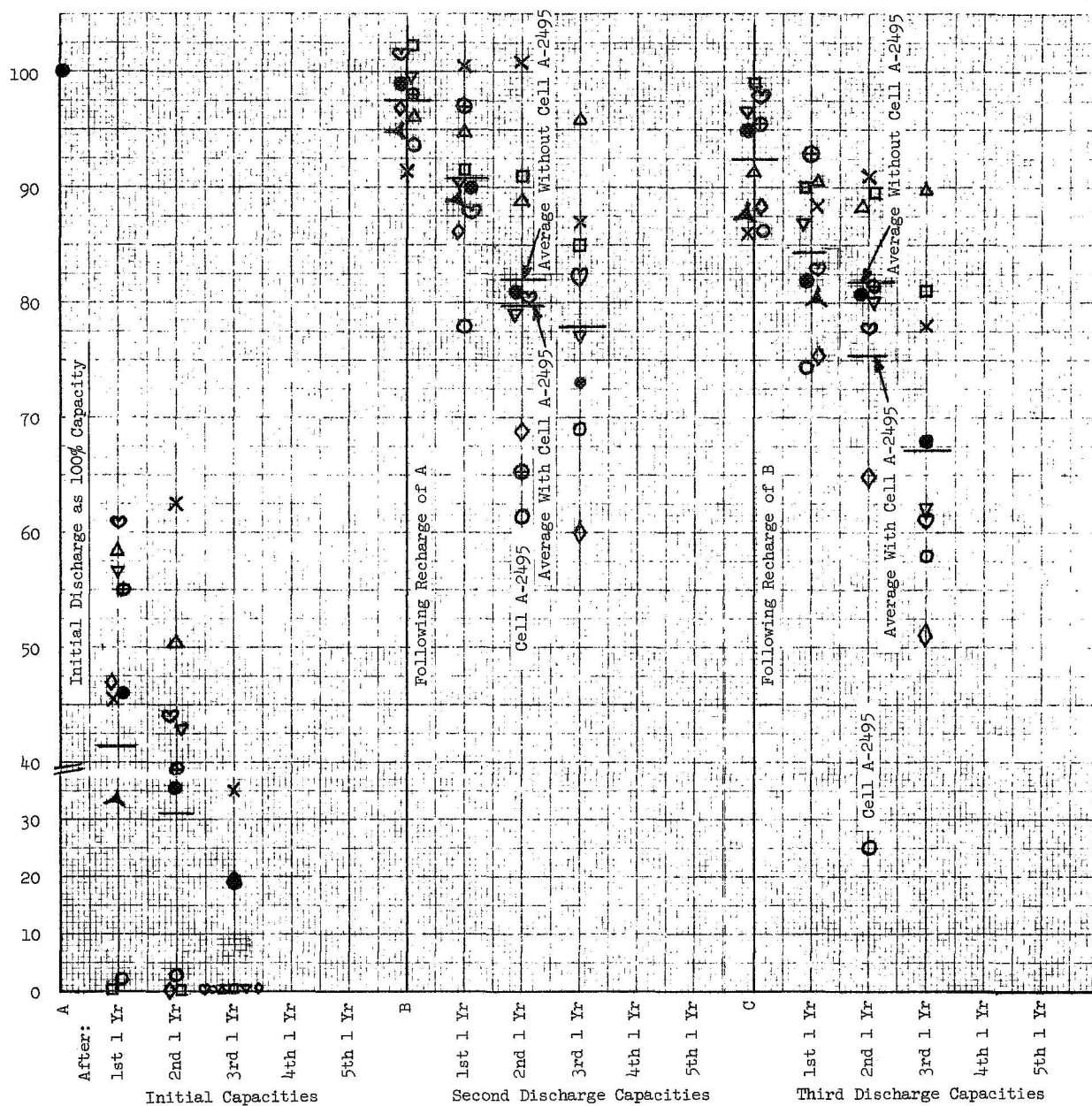
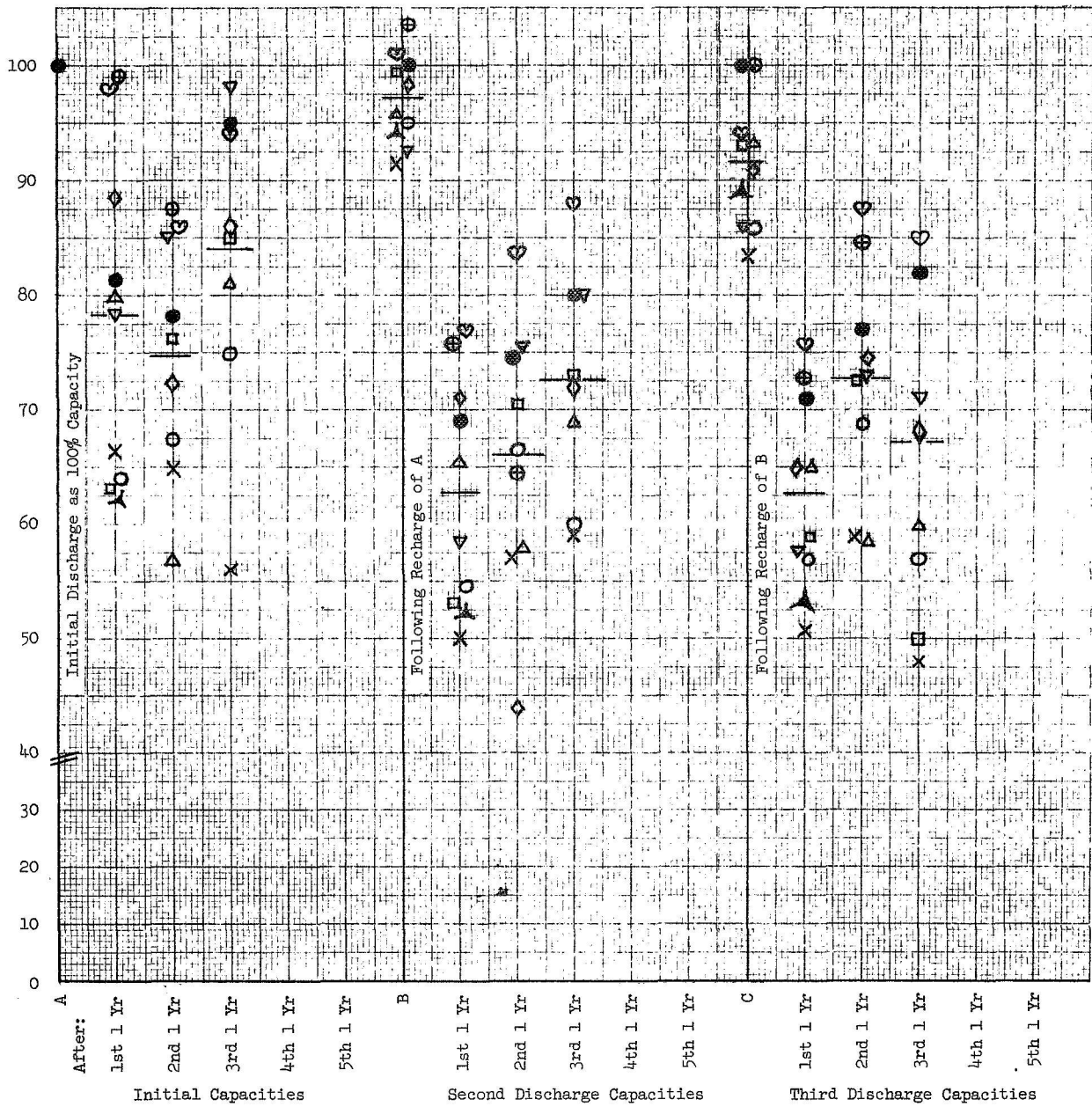
OPEN CIRCUIT STORAGE TEST AT $25^{\circ} \pm 2^{\circ} \text{C}$ INITIAL AND TWO REPEAT CAPACITY TESTS AFTER EACH YEAR OF OPEN CIRCUIT STORAGE
(Each capacity test shown as percentage of initial discharge.)

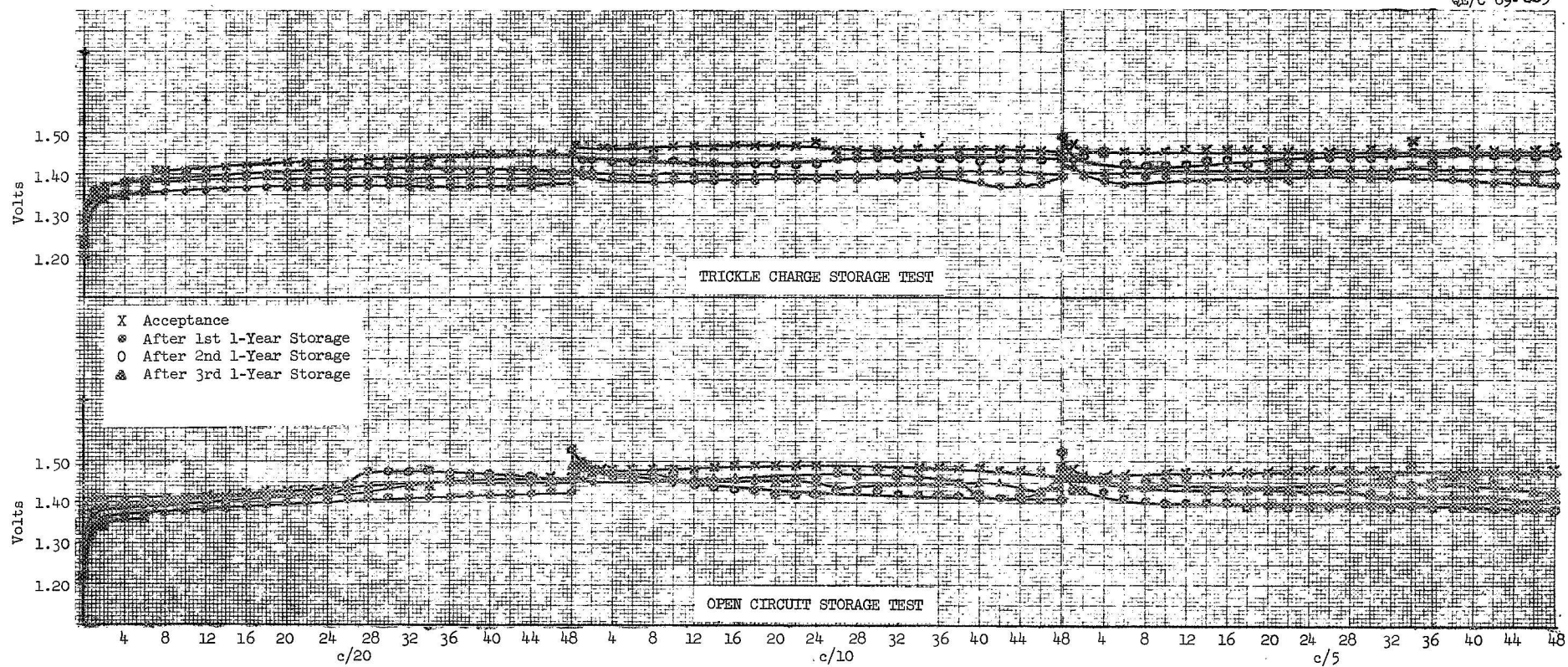
FIGURE 2



TRICKLE CHARGE STORAGE TEST AT $25^{\circ} \pm 2^{\circ} \text{C}$

INITIAL AND TWO REPEAT CAPACITY TESTS AFTER EACH YEAR OF TRICKLE CHARGE STORAGE
(Each capacity test shown as percentage of initial discharge.)

FIGURE 3



OVERCHARGE VOLTAGES (AVERAGE) VERSUS TIME AT c/20, c/10 AND c/5

FIGURE 4

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